

DEC 07 2004

Application Serial No. 10/632,273
Response to September 7, 2004 OA

MI22-2379

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/632,273
Filing Date July 31, 2003
Inventor Warren M. Farnworth et al.
Assignee Micron Technology, Inc.
Group Art Unit 2829
Examiner R. Kobert
Attorney's Docket No. MI22-2379
Customer No. 021567

Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

RESPONSE TO SEPTEMBER 7, 2004 OFFICE ACTION

To: Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: D. Brent Kenady
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Responsive to the Office Action dated September 7, 2004, Applicant amends and
remarks as follows:

AMENDMENTS

Underlines indicate insertions and ~~strikeouts~~ indicate deletions.